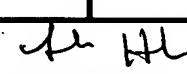
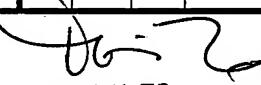


Issue Classification		Application/Control No. 10/717,464	Applicant(s)/Patent under Rexamination SAINT ETIENNE ET AL.
		Examiner Feben M. Haile	Art Unit 2616

ISSUE CLASSIFICATION									
ORIGINAL		INTERNATIONAL CLASSIFICATION							
CLASS	SUBCLASS	CLAIMED		NON-CLAIMED					
370	278	H	04	B	7 /005	/			
CROSS REFERENCES				H	04	L	1 /00	/	
CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			H	04	L	12 /56	/	
370	235	409						/	
								/	
								/	
								/	
								/	
 Feben Micael Haile 9/14/2007 (Assistant Examiner) (Date)				 DORIS H. TO SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2600				Total Claims Allowed: 10	
 Michael J. Ryan 8/17/07 (Legal Instruments Examiner) (Date)								O.G. Print Claim(s)	O.G. Print Fig.
								1	3

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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